



Patent

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Attorney's Docket No. 027260-485

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Takehiko SHIMOMURA, et al.

Application No.: 09/939,602

Filed: August 28, 2001

For: SCAN TEST SYSTEM FOR

SEMICONDUCTOR DEVICE

Group Art Unit: 2133

Examiner: Unassigned

REQUEST FOR CORRECTED OFFICIAL FILING RECEIPT

Assistant Commissioner for Patents Office of Initial Patent Examination Customer Service Center Washington, D.C. 20231

Sir:

Enclosed is a copy of the Official Filing Receipt marked in red to show correction that is needed. The correction is as follows.

Under Foreign Applications, delete [2001-90830] and insert --2001-090830--.

Issuance of a corrected Official Filing Receipt is respectfully requested.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

By: (

Ellen Marcie Emas Registration No. 32,131

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Date: November 21, 2001



United States Patent and Trademark Office

COMMISSIONER FOR PATENTS United States Patent and Trademark Office Washington, D.C. 20231 www.uspto.gov

APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY.DOCKET.NO	DRAWINGS	TOT CLAIMS	IND CLAIMS
09/939,602	08/28/2001	2133	710	027260-485	4	6	2

CONFIRMATION NO. 3292

FILING RECEIPT

OC000000006803378

Platon N. Mandros BURNS, DOANE, SWECKER & MATHIS, L.L.P. P.O. Box 1404 Alexandria, VA 22313-1404

Date Mailed: 09/27/2001

Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

Applicant(s)

Takehiko Shimomura, Tokyo, JAPAN; Masayuki Konishi, Tokyo, JAPAN;

Domestic Priority data as claimed by applicant

Foreign Applications

JAPAN 2001-90830 03/27/2001 2001-090830

If Required, Foreign Filing License Granted 09/27/2001

Projected Publication Date: 10/03/2002

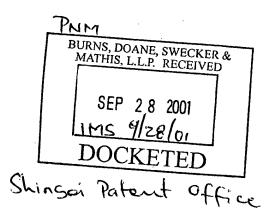
Non-Publication Request: No

Early Publication Request: No

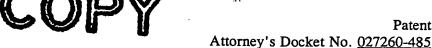
Title

Preliminary Class

Scan test system for semiconductor device



Patent



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of	
Takehiko SHIMOMURA et al.) Group Art Unit: Unassigned
Application No.: Unassigned) Examiner: Unassigned
Filed: August 28, 2001)
For: SCAN TEST SYSTEM FOR SEMICONDUCTOR DEVICE	AECENE DEC 05 2001 Technology Contact 230 ENTION PRIORITY
CLAIM FOR CONVE	ENTION PRIORITY

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

The benefit of the filing date of the following prior foreign application in the following foreign country is hereby requested, and the right of priority provided in 35 U.S.C. § 119 is hereby claimed:

Japanese Patent Application No. 2001-090830

Filed: March 27, 2001

In support of this claim, enclosed is a certified copy of said prior foreign application. Said prior foreign application was referred to in the oath or declaration. Acknowledgment of receipt of the certified copy is requested.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

Date: August 28, 2001

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PATENT OFFICE JAPANESE GOVERNMENT

This is to certify that the annexed is a true copy of the following application as filed with this Office.

Date of Application: March 27, 2001

Application Number : Japanese Patent Application No. 2001-090830

Applicant(s) : MITSUBISHI DENKI KABUSHIKI KAISHA

This 20th day of April, 2001

Commissioner,

Japan Patent Office Kozo OIKAWA



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CONFIRMATION NO. 3292

SERIAL NUMB 09/939,602		FILING DATE 08/28/2001 RULE	C	CLASS 714	GROUP ART UNIT 2133			ATTORNEY DOCKET NO. 027260-485		
APPLICANTS								_		
Takehiko Shimomura, Tokyo, JAPAN; Masayuki Konishi, Tokyo, JAPAN;										
** CONTINUING DATA **********************************										
** FOREIGN APPLICATIONS ************************************									`.	
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 09/27/2001										
Foreign Priority claime 35 USC 119 (a-d) cond met Verified and Acknowledged	ditions	yes no Net after Allowance infiner's/Signature	er D.G tials	STATE OR COUNTRY JAPAN	DRA	ETS WING 1	TOTA CLAI 6		INDEPENDENT CLAIMS 2	
ADDRESS Platon N. Mandros BURNS, DOANE, SWECKER & MATHIS, L.L.P. P.O. Box 1404 Alexandria ,VA 22313-1404										
TITLE										
Scan test system	for s	emiconductor device								
	FEES: Authority has been given in Paper No to charge/credit DEPOSIT ACCOUNT No for following:					☐ All Fees				
						1.16 Fees (Filing)				
FILING FEE RECEIVED					NT	☐ 1.17 Fees (Processing Ext. of time)				
710						☐ 1.18 Fees (Issue)				
						Other				
						☐ Credit				